September 1996

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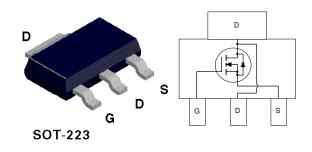
NDT453N N-Channel Enhancement Mode Field Effect Transistor

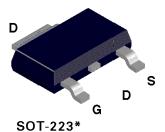
General Description

Power SOT N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to minimize on-state resistance and provide superior switching performance. These devices are particularly suited for low voltage applications such as notebook computer power management and other battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

Features

- $\label{eq:rescaled} \begin{array}{c} \bullet \ \ \, 8A, \, 30V. \ R_{_{DS(ON)}} = 0.028\Omega \ \ \, @V_{_{GS}} = 10V. \\ R_{_{DS(ON)}} = 0.042\Omega \ \ \, @V_{_{GS}} = 4.5V. \end{array}$
- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability in a widely used surface mount package.





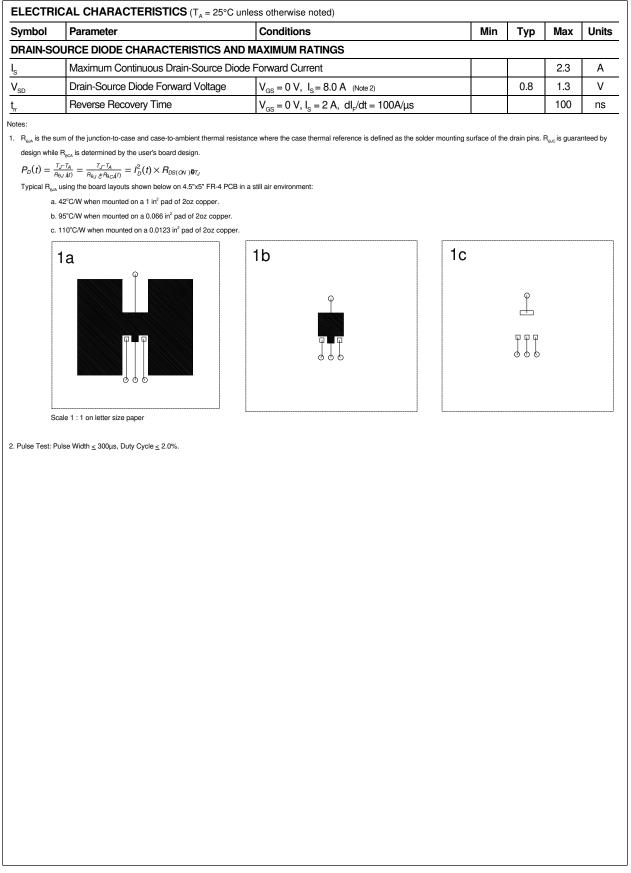
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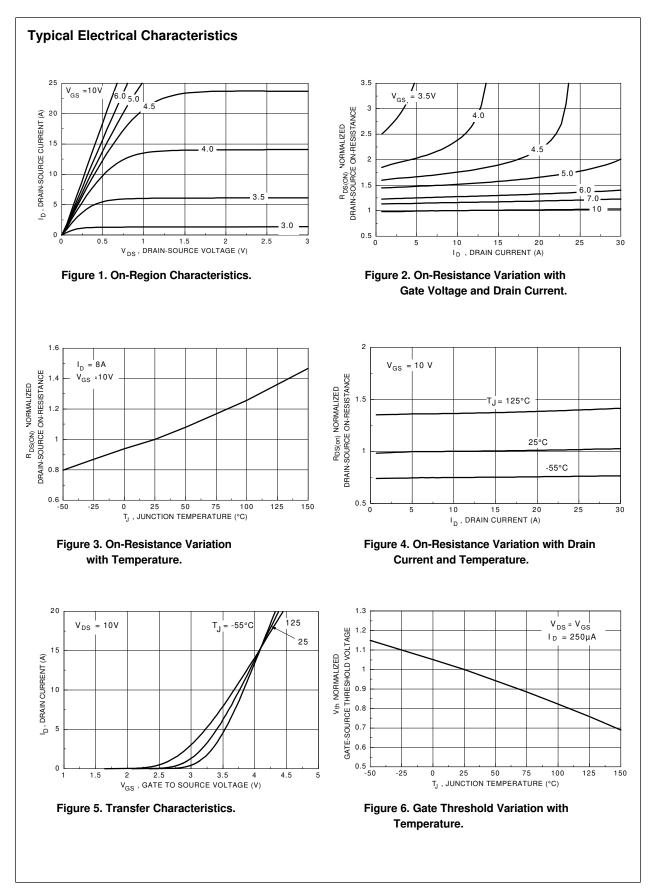
Absolute Maximum Ratings T.= 25°C unless otherwise not

Symbol	Parameter		NDT453N	Units
V _{DSS}	Drain-Source Voltage		30	V
V_{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current - Continuous	(Note 1a)	±8	A
	- Pulsed		±15	
P _D	Maximum Power Dissipation	(Note 1a)	3	W
		(Note 1b)	1.3	
		(Note 1c)	1.1	
T _J ,T _{STG}	Operating and Storage Temperature Range		-65 to 150	°C
THERMA	L CHARACTERISTICS			
R _{ÐJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	42	°C/W
R _{eJC}	Thermal Resistance, Junction-to-Case	(Note 1)	12	°C/W

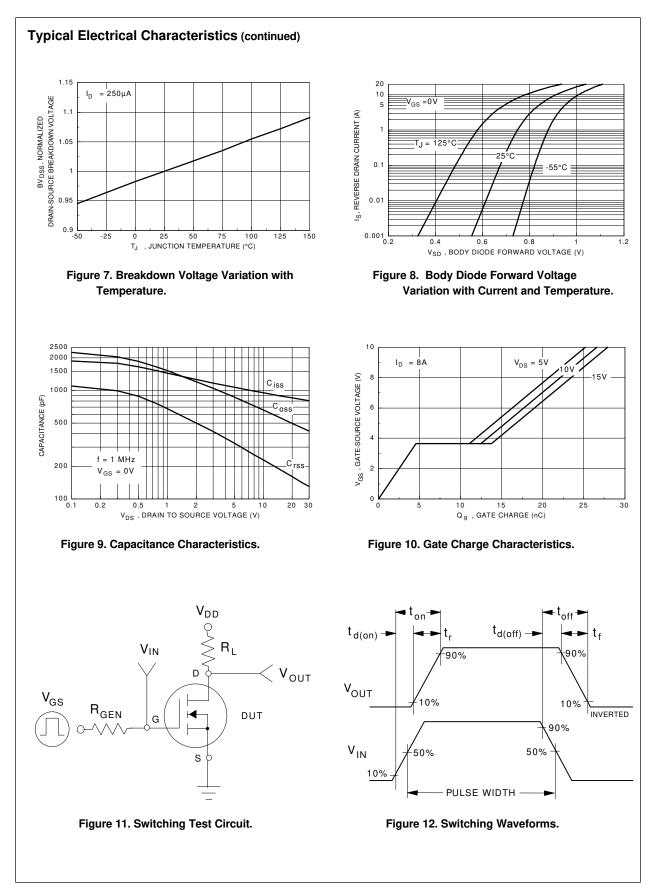
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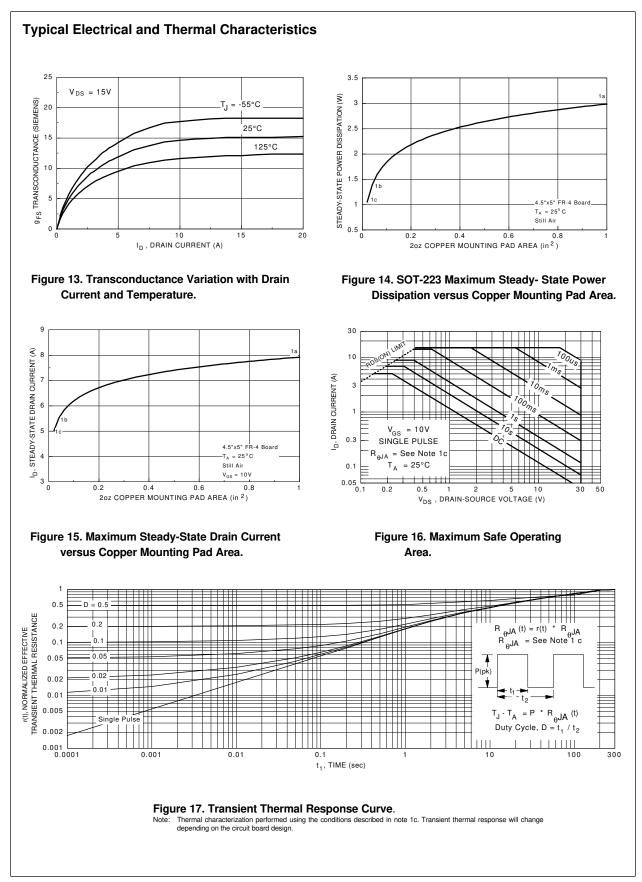
Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHA	RACTERISTICS						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{D} = 250 \mu\text{A}$		30			V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 V, V_{GS} = 0 V$				1	μA
			T _J = 55°C			10	μA
I _{GSSF}	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
	ACTERISTICS (Note 2)				L	1	
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		1	2	3	V
.,			T _J = 125°C	0.7	1.5	2.2	1
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, I_{D} = 8.0 \text{ A}$			0.022	0.028	Ω
-(-)			T _J = 125°C		0.03	0.045	
		$V_{GS} = 4.5 \text{ V}, I_{D} = 6.7 \text{ A}$			0.035	0.042	
			T _J = 125°C		0.047	0.075	
I _{D(on)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 5 \text{ V}$		15			Α
		$V_{GS} = 4.5 \text{ V}, V_{DS} = 5 \text{ V}$		10			
9 _{FS}	Forward Transconductance	$V_{\rm DS} = 15 \text{ V}, \text{ I}_{\rm D} = 8.0 \text{ A}$			14		S
DYNAMIC	CHARACTERISTICS	·					
C _{iss}	Input Capacitance	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			890		pF
C _{oss}	Output Capacitance				560		pF
C _{rss}	Reverse Transfer Capacitance				190		pF
SWITCHIN	IG CHARACTERISTICS (Note 2)						-
t _{D(on)}	Turn - On Delay Time	$V_{DD} = 25 \text{ V}, \text{ I}_{D} = 1 \text{ A},$ $V_{GEN} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$			10	15	ns
ţ	Turn - On Rise Time				20	35	ns
t _{D(off)}	Turn - Off Delay Time				40	50	ns
t,	Turn - Off Fall Time				35	50	ns
Q _g	Total Gate Charge	$V_{DS} = 15 \text{ V}, \text{ I}_{D} = 8.0 \text{ A}, \text{ V}_{GS} = 10 \text{ V}$			28	35	nC
Q _{gs}	Gate-Source Charge				4.5		nC
Q _{gd}	Gate-Drain Charge				9.5		nC





NDT453N Rev. D1





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